

Gimp Testing Update

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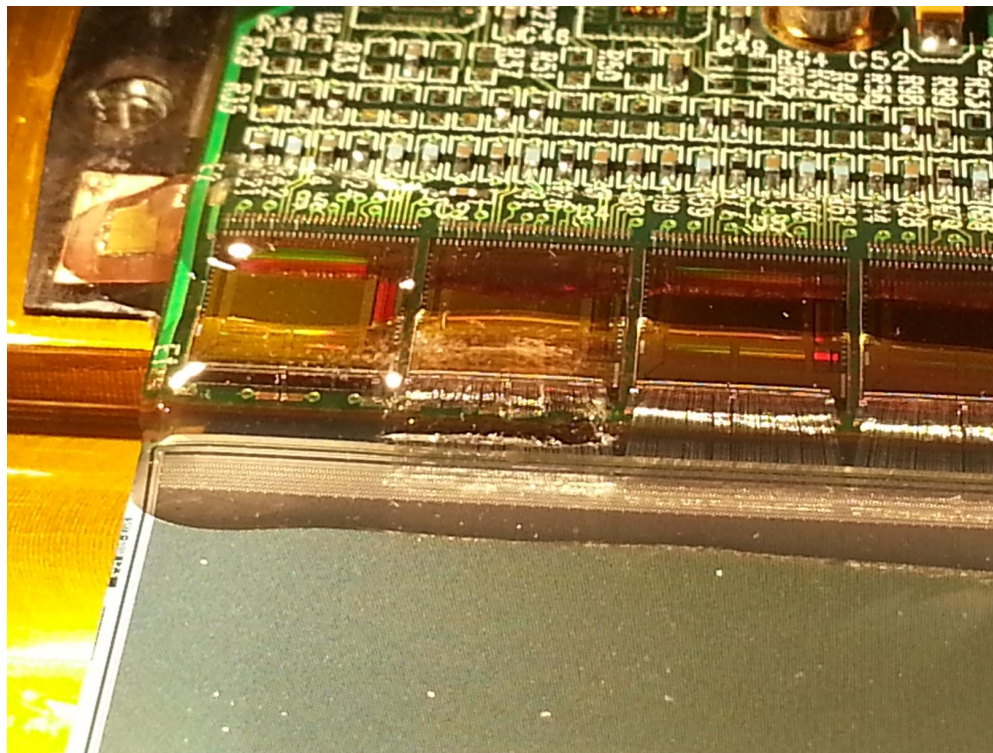
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October 28, 2013

Heavy Photon Search SVT Meeting

Testing Overview

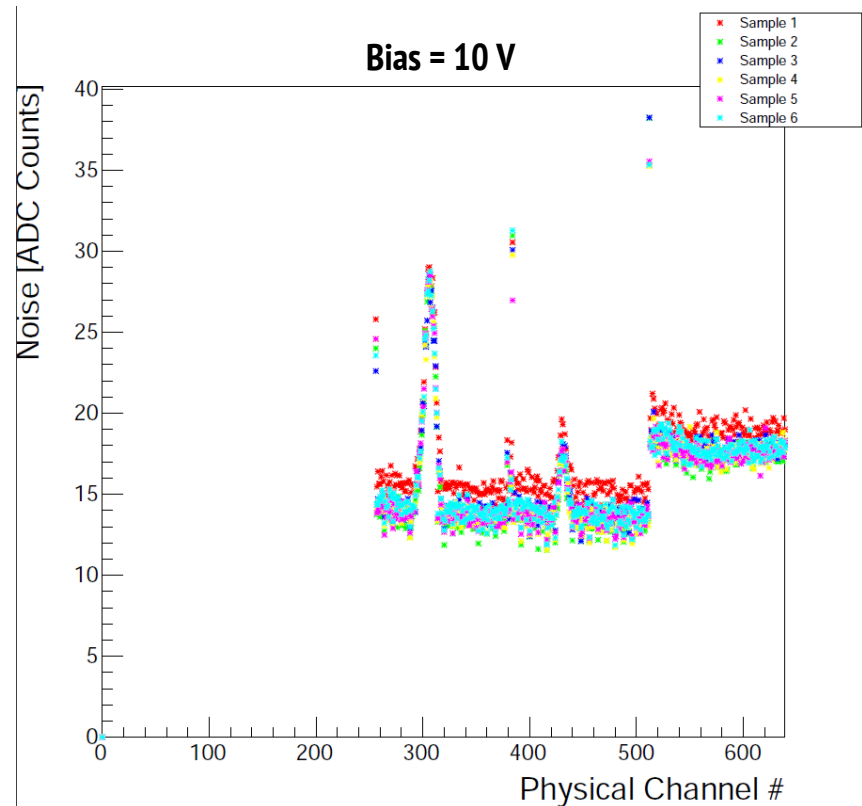
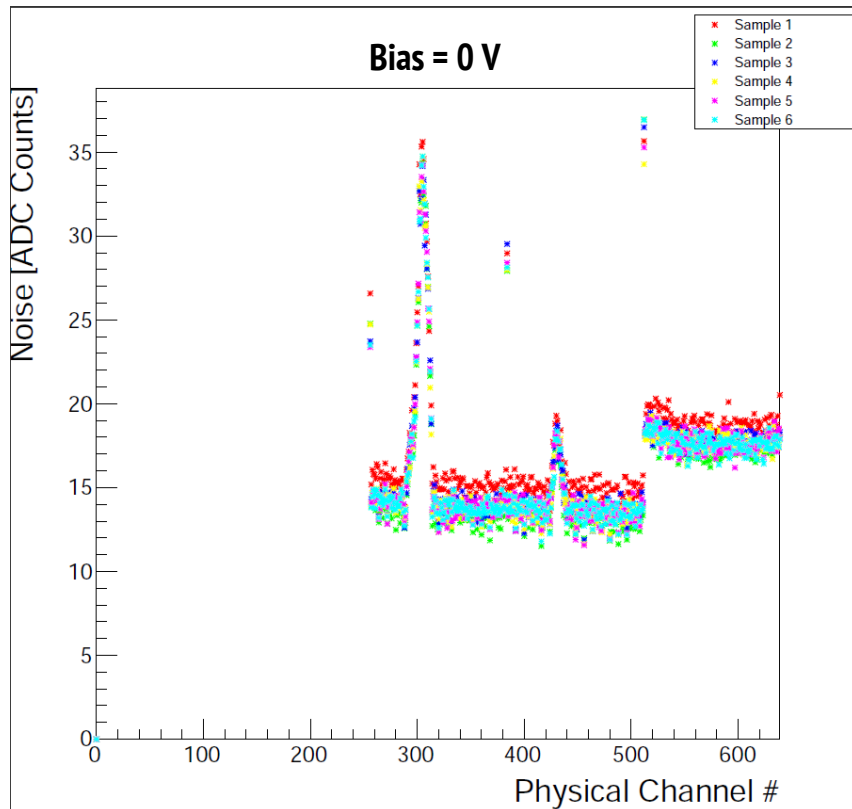
- ❖ Removed wirebonds from the APV25 nearest the unbonded APV25



- ❖ Took baseline runs with the sensor bias ranging from 0 - 200 V
- ❖ Took single calibration run at 180 V
- ❖ Note: Only the unbonded APV25 and the two misbehaving APVs are present in the plots
- ❖ All data can be found here: http://www.slac.stanford.edu/~omoreno/hm_plots/gimp/

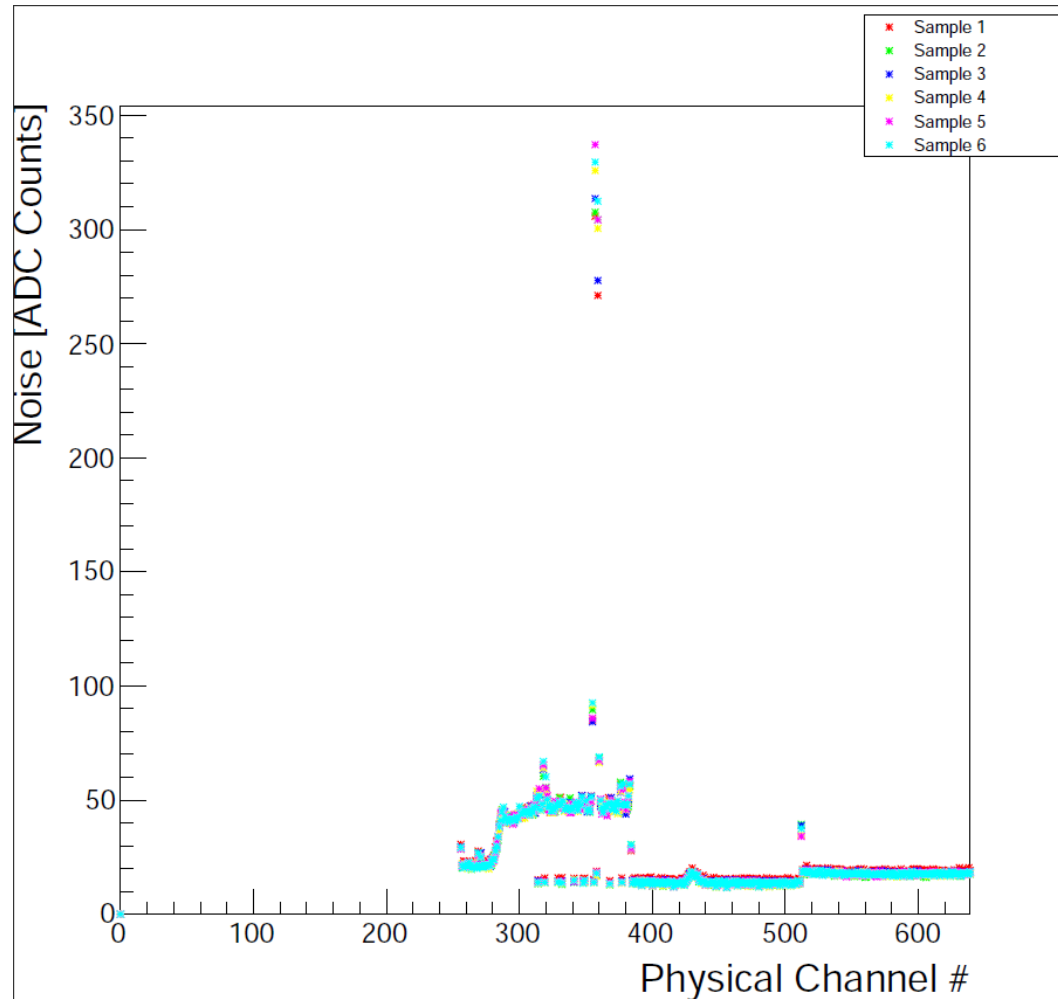
Run with sensor bias at 0 V and 10 V

- ❖ Noise for unbonded APV is as expected at ~20 ADC counts
- ❖ Noise for misbehaving APVs is ~15 ADC counts
 - Expected the noise of the APV with the pulled wirebonds to be similar to the unbonded APV
 - Expected large noise for bonded chip
- ❖ “Noise spikes” are present in the same region on both misbehaving chips



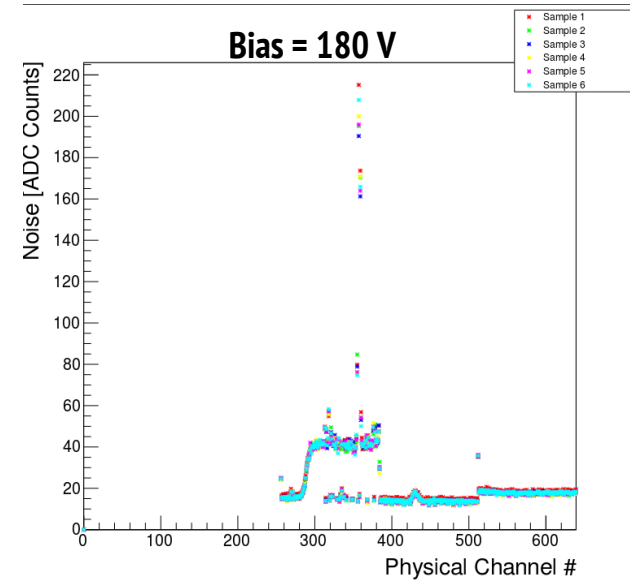
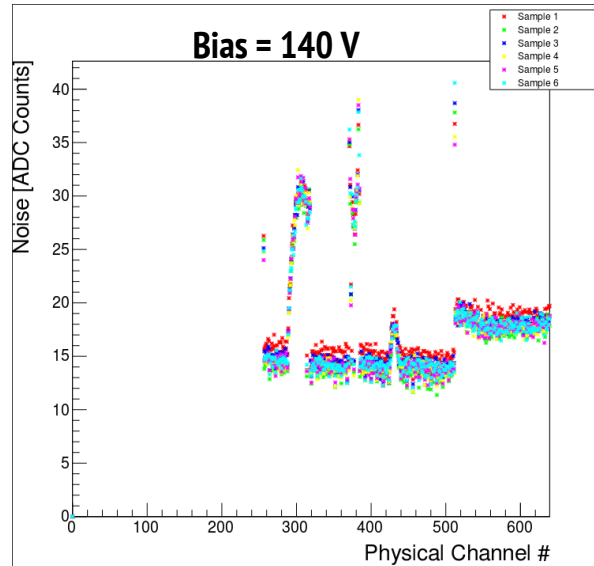
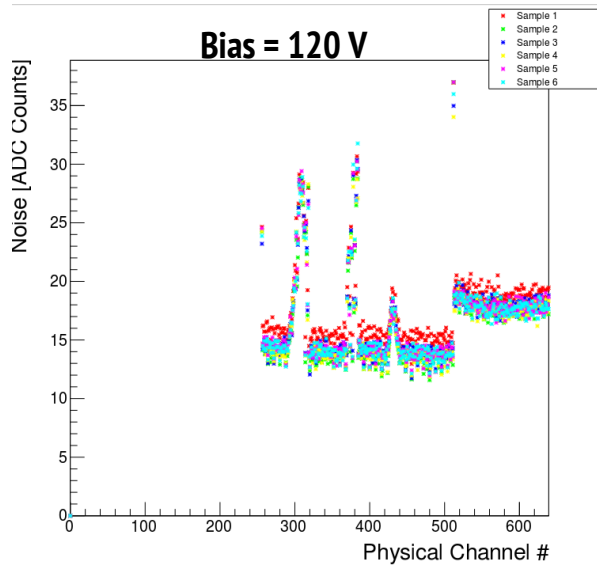
Run with sensor bias at 180 V

- ❖ Same noise pattern which was observed before is present on bonded chip



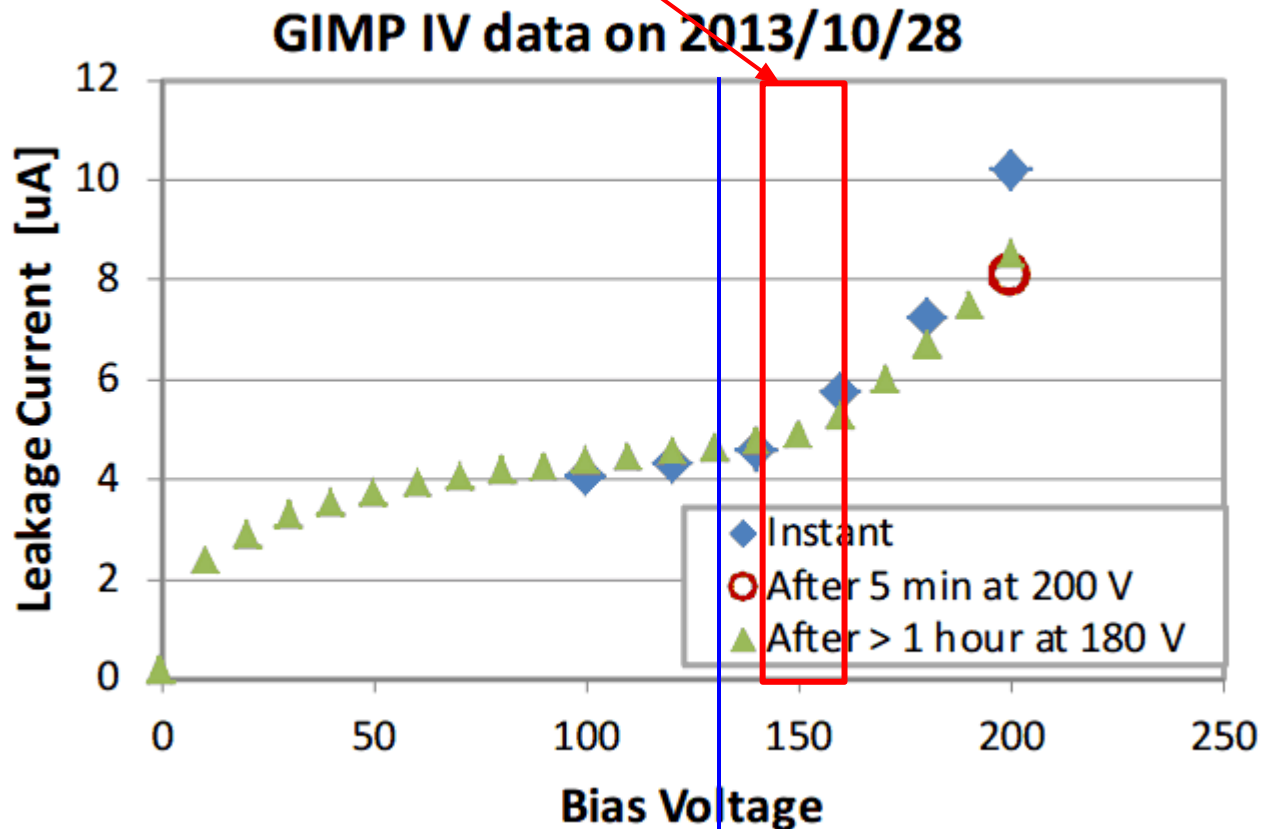
Run with sensor bias at 120 V, 140 V and 160 V

- ❖ Noise pattern is gone at 120 V and 140 V and present at bias voltages ≥ 160 V
 - Noise at 120 V looks like that observed at 0 V and 10 V
 - Additional noise spike has appeared at 120 V and 140 V



Leakage Current

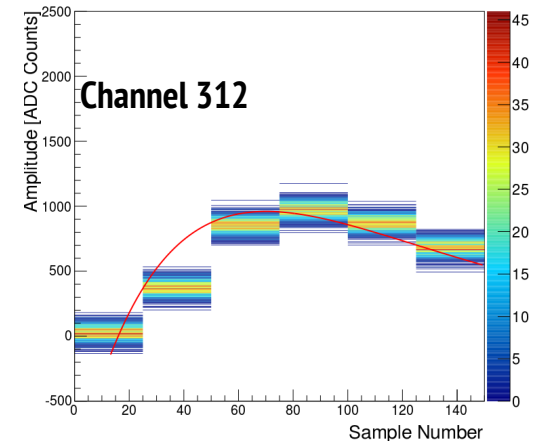
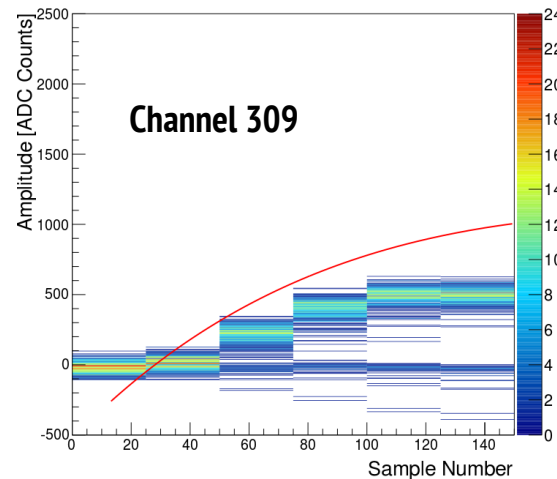
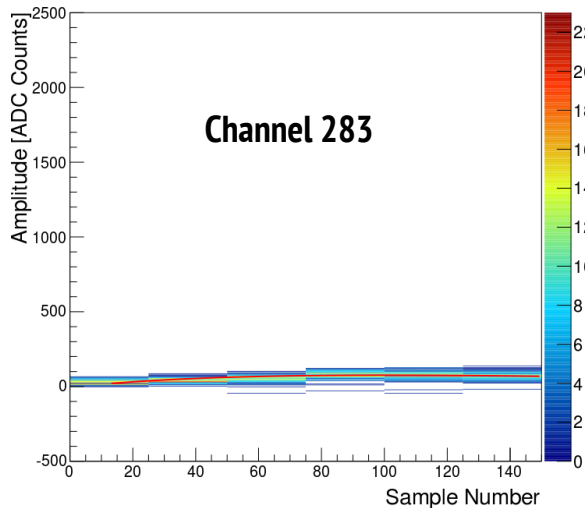
- ❖ Bias region where noise pattern emerges seems to coincide with sudden increase in leakage current



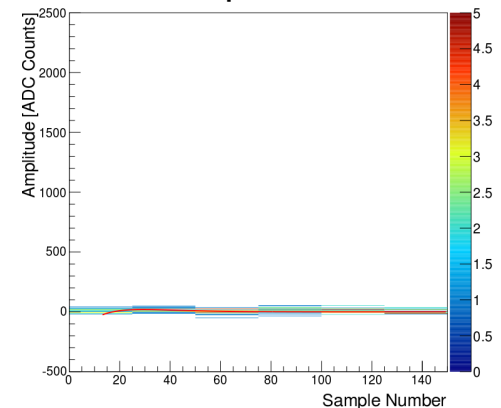
Depletion Voltage at 132 V

Calibration Response

- ❖ Calibration run taken with sensor biased to 180 V
- ❖ Calibration response of unbonded channels looks as expected
- ❖ Response of the bonded chip is either ~ 0 or is low (~ 500 ADC Counts)
 - Response of calibration group 0 starts out strange but improves across the chip



- ❖ The channels of the APV with pulled wirebonds do not respond to a calibration pulse
 - Seems to be indicating that the chips are dead
 - Trying to understand the noise pattern is irrelevant at this point
 - Sensor may or may not be damaged; It's hard to tell without IV curves taken before the test



Calibration Response Overview

